

**Notice of References Cited**

Application/Control No.

09/988,585

Applicant(s)/Patent Under  
Reexamination  
HORIKOSHI ET AL.

Examiner

Thien F Tran

Art Unit

2811

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,118,151	09-2000	Tsutsu, Hiroshi	257/347
	B	US-6,168,980	01-2001	Yamazaki et al.	438/162
	C	US-6,025,630	02-2000	Yamazaki et al.	257/347
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 8-195494	07-1996	Japan	Abe et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

Copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.